

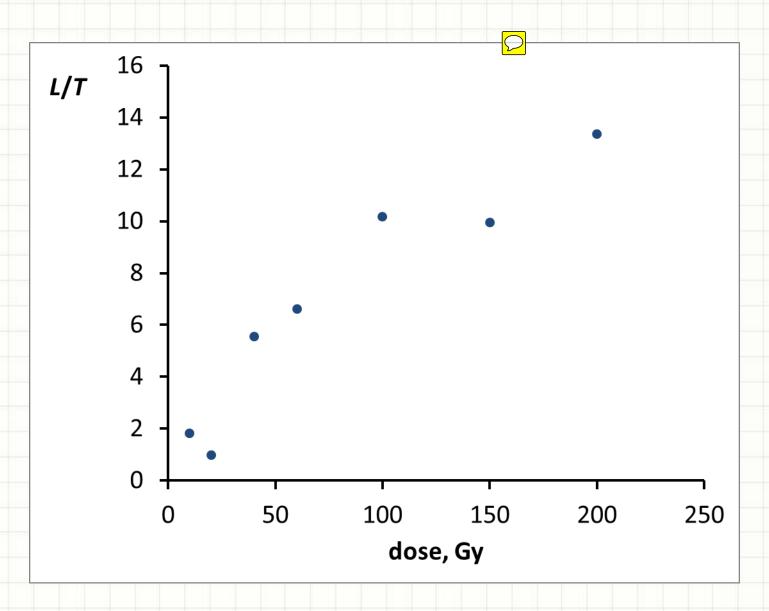
# DATA REDUCTION IN LUMINESCENCE MEASUREMENTS

Andrzej Bluszcz LED2011 Workshop Toruń, 10 July 2011

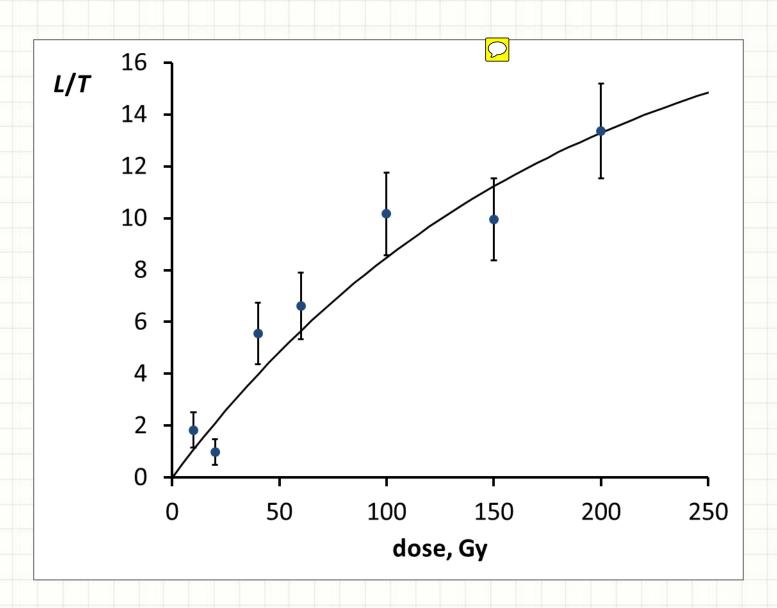
### Plan of lecture

- Introduction
- Measurement errors and uncertainties
- Reduction of data
  - analysis of OSL shine down curves
  - analysis of OSL growth curves calibration
  - calculation of D<sub>E</sub> value and reporting
- Summary

### Introduction



### Introduction



## Measurement errors and uncertainties

Measurement errors random errors systematic errors

Accuracy and precision of measurements

Uncertainty of measurements

### Measurement errors



Error is the difference between the result of measurement and the value of the measurand.

Measurement errors are usually categorized as **random errors** and **systematic errors**.

When measurements are repeated under stable conditions:

- random errors have unpredictable values, that follow some statistical distribution (normal, Poisson, etc.),
- systematic errors have the same value.

### Measurement errors

A reason for a random error is all uncontrolled factors that influence the result of measurement or the stochastic nature of the process (radioactive or excited state decay, interaction of radiation with matter, etc.).

A reason for a systematic error may be incorrectly calibrated meter, improper physical model used in the measurement process (a real pendulum described as a mathematical pendulum), etc.

### Accuracy and precision

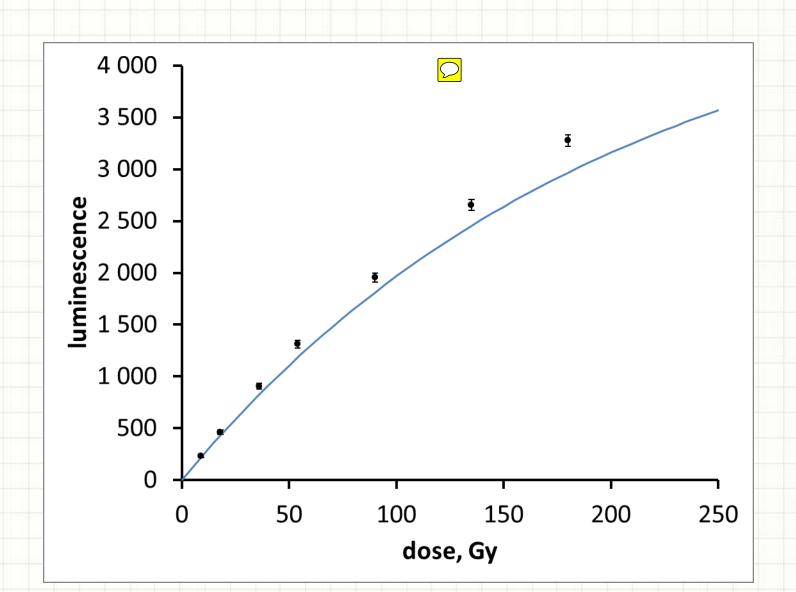
**Accuracy** – concordance of the mean value of measurements with the value of measurand

**Precision** – concordance of results of repeated measurements (under same conditions)

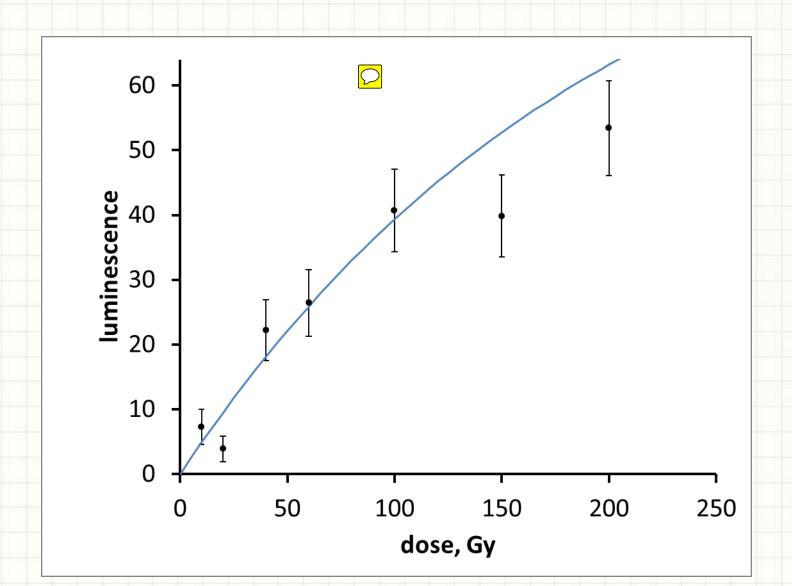




Systematic errors influence accuracy, but not precision.



Random errors influence precision, but not accuracy.



# Uncertainty of result of measurement

Uncertainty is a parameter associated with the result of measurement, that characterizes the dispersion of results.

The basic type of uncertainty is the standard uncertainty which is a standard deviation of results (square root of variance of results).

### Reduction of data

Luminescence signals after regenerative dose and test dose are usually denoted as  $L(D_{reg})$ ,  $T(D_{test})$ , their ratio is a normalized OSL and let us denote it by

$$P = \frac{L}{T}$$

They are obtained from analysis of an OSL shine down curve by either

- simple integration and subtraction or by
- isolating the fast OSL component through a complex curve fitting procedure.

### Analysis of OSL shine down curve



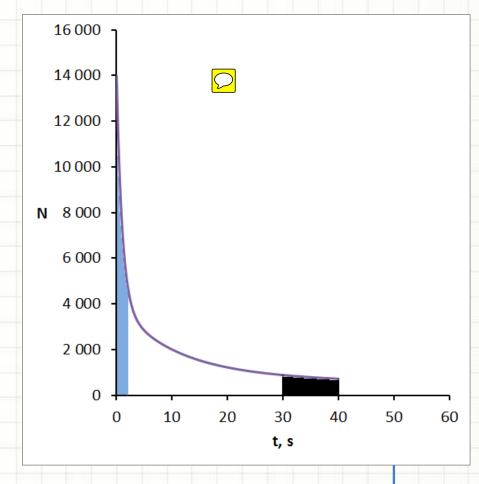
$$N_f = \sum_{i=1}^f N_i \qquad \qquad t_f = \sum_{i=1}^f t_i$$

$$N_b = \sum_{i=l-b+1}^{l} N_i$$
  $t_b = \sum_{i=l-b+1}^{l} t_i$ 

$$u(N) = k\sqrt{N}, k \ge 1$$
  $u(t) = 0$ 

$$L = N_f - N_b \frac{t_f}{t_b}$$

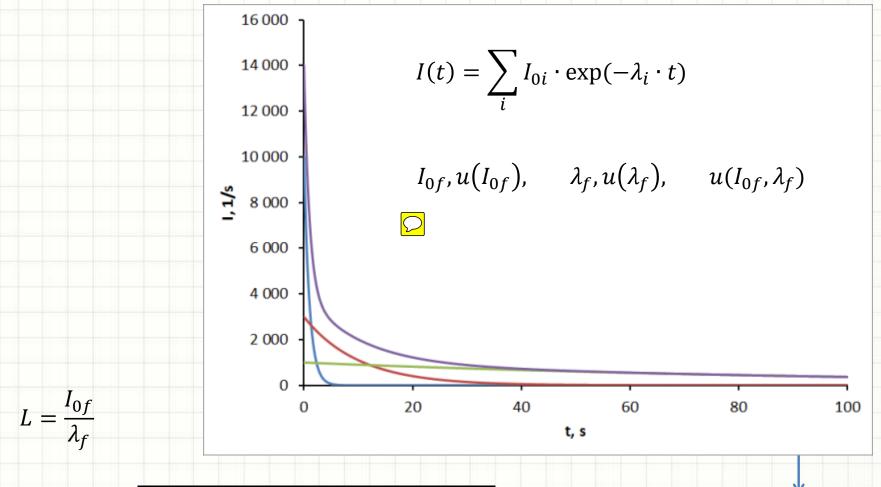
$$u_c(L) = \sqrt{u^2(N_f) + u^2(N_b) \left(\frac{t_f}{t_b}\right)^2}$$



L,  $u_c(L)$  $T, u_c(T)$ 

### $\bigcirc$

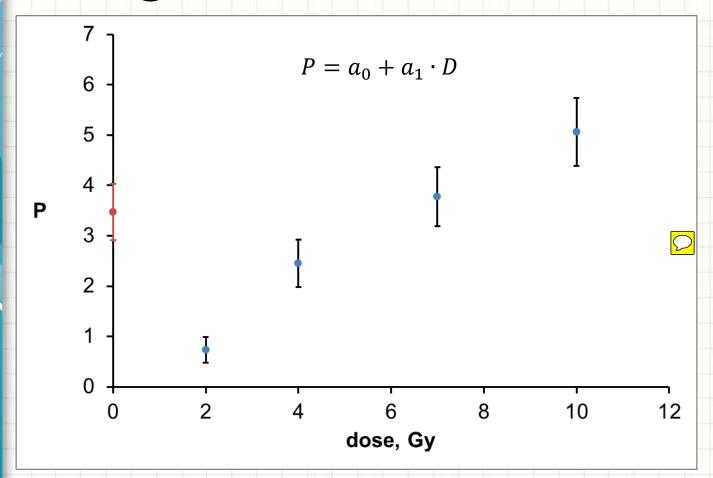
### Analysis of OSL shine down curve



$$u_c(L) = L \sqrt{\left[\frac{u(I_{0f})}{I_{0f}}\right]^2 + \left[\frac{u(\lambda_f)}{\lambda_f}\right]^2 - 2\frac{u(I_{0f}, \lambda_f)}{I_{0f} \cdot \lambda_f}}$$

 $L, u_c(L)$  $T, u_c(T)$ 

### OSL growth



Fitting the linear function by LSM yields the calibration parameters

$$a_0, u(a_0), \quad a_1, u(a_1), \quad u(a_0, a_1)$$

### that enable calculation of the absorbed equivalent dose:



$$u_c(D_E) = \sqrt{\frac{u_c^2(P_0)}{a_1^2} + \frac{u^2(a_0)}{a_1^2} + \frac{(P_0 - a_0)^2}{a_1^4} u^2(a_1) + 2\left(\frac{P_0 - a_0}{a_1^3}\right) u(a_0, a_1)}$$

# Uncertainty of calibration of the beta source

Assume that the relative standard uncertainty of the source calibration is p (for example 0,02 or 2%).

That means, we have to add this contribution to obtain the overall uncertainty in  $D_E$ 

$$u_c(D_E) = \sqrt{\frac{u_c^2(P_0)}{a_1^2} + \frac{u^2(a_0)}{a_1^2} + \frac{(P_0 - a_0)^2}{a_1^4}} u^2(a_1) + 2\left(\frac{P_0 - a_0}{a_1^3}\right) u(a_0, a_1) + (pD_E)^2$$





### Summary

We have seen how a dozen of OSL curves, containing thousands of raw numerical data, may be reduced, resulting in a value of equivalent dose and its combined uncertainty:

 $D_E$ ,  $u_c(D_E)$ 



# Thank You!